

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10585187	KISHIMOTO ET AL.
	<b>Examiner</b> HEE-YONG KIM	<b>Art Unit</b> 2621

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
348	92	3/30/2010	H.K

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
(camera or photogrpah\$4) and inspect\$4	3/30/2010	H.K
(camera or photogrpah\$4) and inspect\$4 and automatic focus\$4	3/30	H.K
(camera or photogrpah\$4) and inspect\$4 and automatic focus\$4 and swivel	3/30	H.K
(camera or photogrpah\$4) and inspect\$4 and automatic focus\$4 and (field near view)	3/30	H.K
(camera or photogrpah\$4) and inspect\$4 and (inspect\$4 with paste)	3/30	H.K
(camera or photogrpah\$4) and inspect\$4 and (inspect\$4 with paste) and strip	3/30	H.K
camera and (inspection or inspecting) with (paste or sealant or liquid gasket)	4/5	H.K
camera and (inspection or inspecting) with (paste or sealant or liquid gasket) and (auto focus or auto exposure)	4/5	H.K
paste with liquid gasket and seal\$4	4/5	H.K

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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